ASTER Technologies introduces a new generation of "easy to use" test coverage analysis tools

Press Release:

Cesson-Sévigné, FRANCE /Electronica 2008, Munich, Germany, 24th October 2008.

During Electronica 2008 at the New Munich Trade Fair Centre, ASTER Technologies the leading supplier in Board-Level Testability and Test Coverage analysis tools, introduces a new generation of "easy to use" test coverage analysis tools. This new range is powered by TestWay, the world-wide reference coverage analysis tool, helping users to quantify and qualify the test coverage for a wide range of inspection and test equipments. More than 20 test models including AOI, AXI, BST, FPT, ICT, and MDA are currently supported.

These products have been developed to address the many challenges that developers face today, such as: shrinking release cycles, budget compression and improvement in product quality. More specifically, at a time when customers expect to buy "good boards only", it becomes mandatory to understand the ability of a test to catch defects.
In other words "how good is the test coverage?"

With this in mind, this new generation of products has been designed for use by electronic board manufacturers (CMs) and their customers, the original equipment manufacturers (OEMs), for providing precise, detailed and impartial test coverage metrics.

ASTER also offer possibilities of license migration, which make it possible to convert a **QuadView-TPQR** configuration into **TestWay Express** or **TestWay** to enable more sophisticated analysis capabilities.

TestWay Express is being previewed at the Electronica show as an alpha release version, to enable customers to view the concept prior to the official release during Q1, 2009, whereas **QuadView-TPQR** is available for immediate purchase.

QuadView-TPQR is a "low-cost" test coverage analysis tool that allows users to compute the test coverage provided by a single piece of test equipment. This software imports the test program or test report, computes the test coverage and generates detailed reports in HTML and MS-EXCEL format.

Board data can be imported directly from test program generation applications created by either Siemens-TestExpert or Mentor Graphics–CAMCAD, in order to visualize the board layout and schematics, and to modelize component class and properties such as number, value and tolerance. **TPQR** checks the ability of each measurement/inspection test to catch certain defect types based on component type, value, tolerance, board connectivity, component location, shape, pitch etc.

It is built around **QuadView**, the suite of next generation viewers for the Electronics Industry. Utilizing this powerful layout and schematic viewer, allows users to visualize coverage at both device and pin level for any of the test/inspection machines used within the industry such as Agilent Technologies: 3070, 5DX, SJ10, SJ50; Teradyne: Z1800, Spectrum, GR228x; TAKAYA: APT800, APT900; AEROFLEX: 42xx; SPEA: 4040; TRI; Orbotech; VI Technology; VISCOM; Asset; Corelis; Goepel; JTAG Technologies and XJTAG.
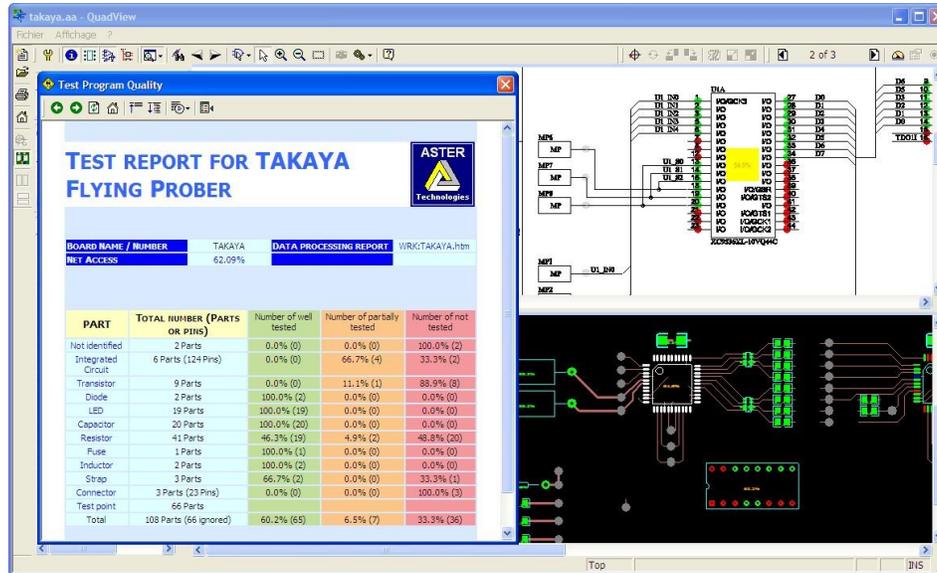

Fig. 1: QuadView-TPQR

TestWay Express provides a more sophisticated level of coverage analysis than QuadView-TPQR because it allows users to combine, within a heterogeneous production line, various types of inspection or test equipments, which allows test coverage qualification to be carried out for each individual test stage, but also consolidates the coverage for the complete production line.

It allows users to calculate the theoretical coverage aligned to various test strategies, prior to product development, in order to identify areas where test coverage can be improved. The ability to optimize the theoretical test coverage will result in higher production yields and ultimately a lower cost of ownership, achieved by improving test effectiveness in terms of test coverage.
Alternatively, **TestWay Express** can conduct a post-development analysis by reading the test programs or coverage reports from the various testers used within the manufacturing cycle, and calculate the real coverage that is achievable. As a result, it is possible to make a comparison between the theoretical and real test coverage.

A variety of test scenarios and test line combinations are created by simply drag and dropping items from the test equipment list to replicate the tester line. By simulating various combinations, customers can leverage the benefits of each solution in reducing the number of false calls, diagnostic inaccuracies and eliminating overlapping tests, resulting in a reduction of the overall test time.

TestWay Express will not only, quickly identify the lack of coverage within an overall, combined test strategy, but will also identify the shortfall for each specific test stage by analyzing the number of defects detected at each stage in the test line.
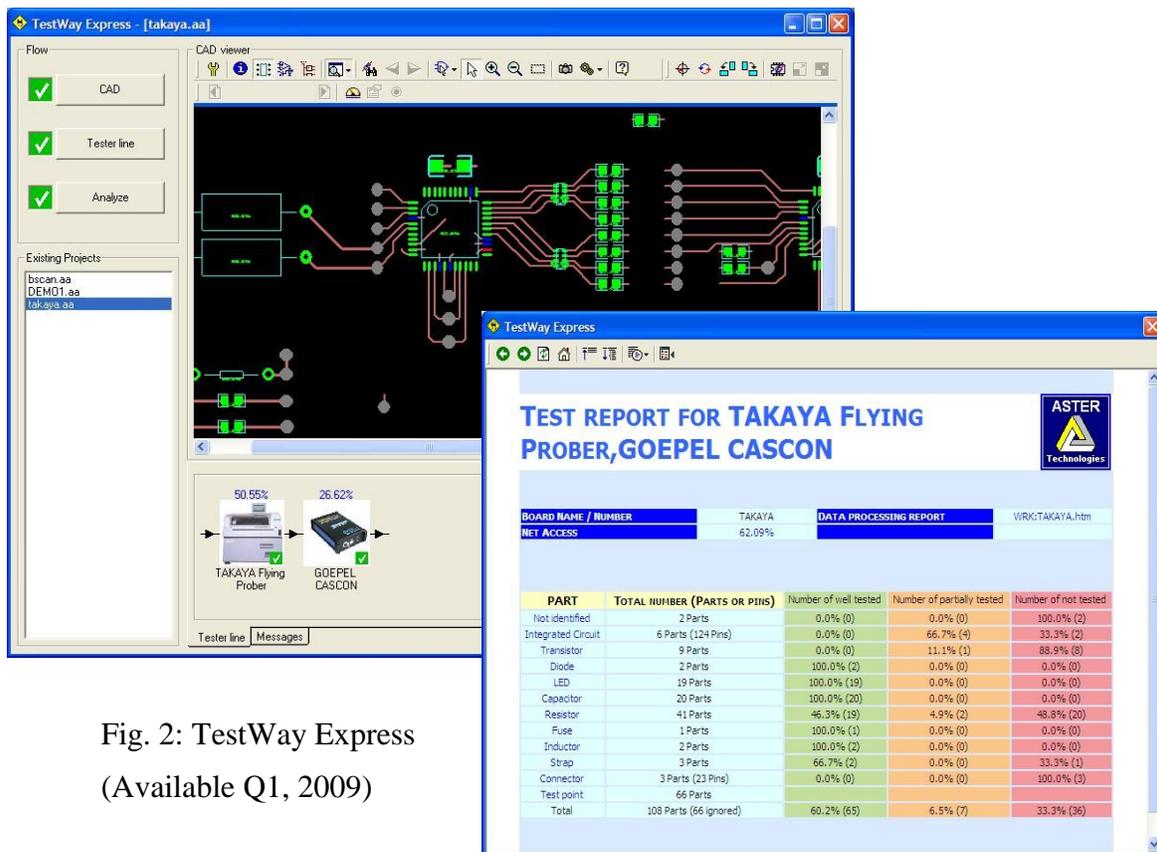

Fig. 2: TestWay Express
(Available Q1, 2009)

About ASTER Technologies

ASTER is the leading supplier in Board-Level Testability analysis tools, capitalizing on proven expertise in board testability and strong customer relations. Founded in 1993, ASTER develops a wide range of products dealing with PCB Testability, Viewing and Quality Management. TestWay is a proven solution, used by many PCB design and manufacturing companies worldwide that provides a unique approach to identify electrical testability requirements and compute theoretical test coverage early in the design chain.

For more information about the company and its solutions, please visit www.aster-technologies.com or call ASTER on +33 299 83 01 01